

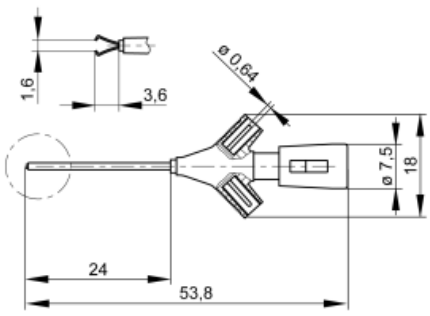


Clamp-type test probe

MICRO-KLEPS



Product	MICRO-KLEPS
description	Miniature clamp-type test probe with rotating grip jaws (SMD technology). The insulated shaft can be bent up to 35°. Suitable for very thin wires and densely packed contact points (1.27 mm IC spacing pitch). Connects with MKL... and MAL...
article-no. / *colour	9739721xx <div style="display: flex; justify-content: space-around; align-items: center;"> <div style="text-align: center;">  00 black </div> <div style="text-align: center;">  01 red </div> </div>
drawing	
	
technical data	
connection	2 x unsprung pin Ø 0.64 mm
rated voltage ⁽¹⁾	30 VAC / 60 VDC
measurement cat. acc. to IEC 61010	CAT I
rated current ⁽¹⁾ (consider derating curve)	2 A

0.64 mm system

material plug	brass, gold plated
housing material	PBT
temperature range acc. To IEC61010 ⁽²⁾	-25 °C to +100 °C
inflammability class acc. to UL 94 (only valid for basic material of housing)	HB
clamp type	rotating grip jaws, tin plated
clamping range	2 mm
standard	IEC 61010

⁽¹⁾ for normal environmental conditions -5°C to +40°C

⁽²⁾ contact the manufacturer for applications at deviating temperature ranges

stand: 13.05.2016